

# ICR HV500-75 set

Near-Field Microprobe 200 kHz - 1 GHz



## Short description

The near-field microprobe is designed for a high-resolution measurement of magnetic near fields. With the ICR H probe the following measurements can be performed:

- Surface Scan via IC according to IEC 61967-3
- Volumenscan via IC
- Pin Scan

The measuring coil at the ICR RF probe head is vertically aligned to the measurement surface.

A preamplifier is integrated into the probe housing and powered by the Bias-Tee.

The ICR near-field probes undergo a quality check before they are delivered. Different reference setup measurements are performed and resulting correction lines are generated. Three different correction lines are determined – a standardized correction line, an H-field correction line, and a current correction line.

Attention: Due to its construction, the ICR probe is sensitive to shock and comes with a protective cap for transport and handling.

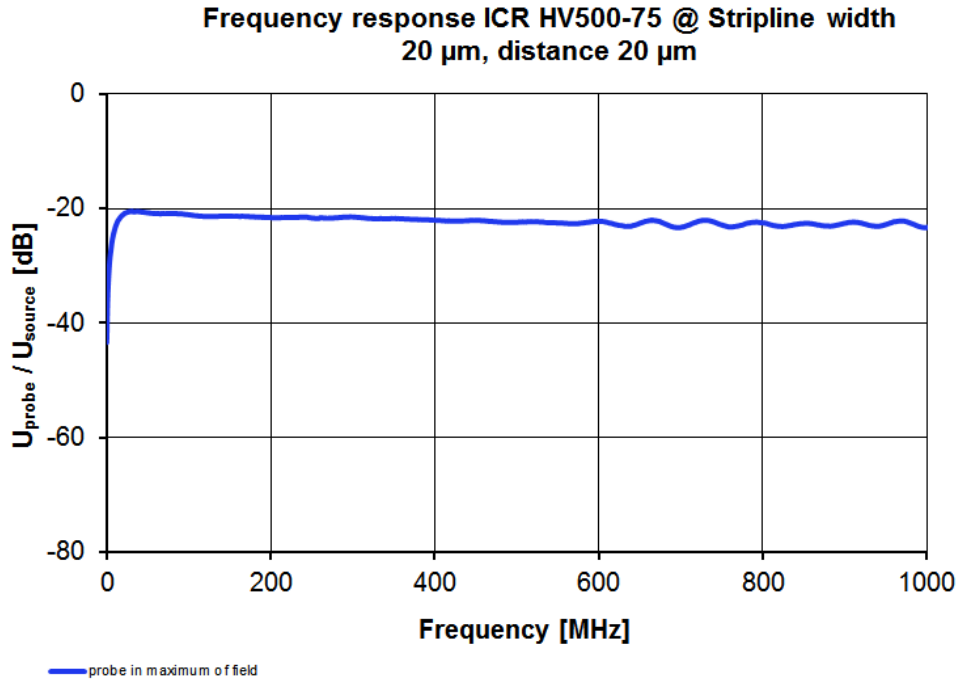
## Scope of delivery

- 1x ICR HV500-75, Near-Field Microprobe 200 kHz to 1 GHz
- 1x BT 706, Bias Tee for Langer probes
- 1x SMA-SMA RA, Cable SMA-SMA, right angle
- 1x ICR-C, ICR Certificate
- 1x ICR Corr, Correction Curves ICR / USB
- 1x NT FRI EU, Power Supply Unit
- 1x ICR case1, System Case

## Technical parameters

|                   |                   |
|-------------------|-------------------|
| Frequency range   | 200 kHz ... 1 GHz |
| Resolution        | 300 µm            |
| Internal diameter | 500 µm            |

Frequency response



Measuring principles



Design, view 1

### Stripline

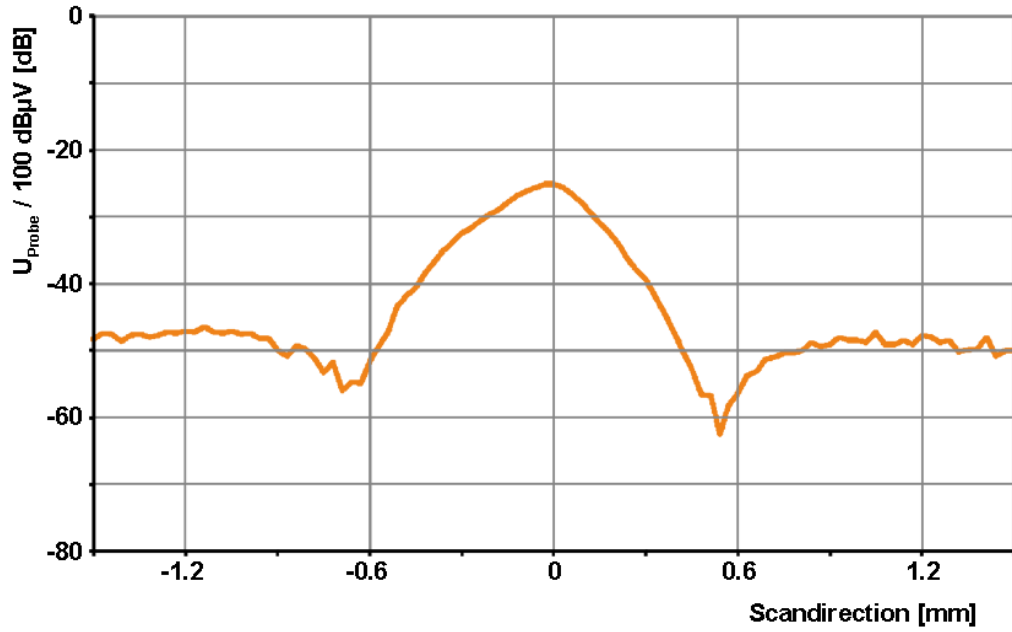


Design, view 2

### Stripline



Transverse profile



ICR HV500-75



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BT 706 bias tee



Scope of delivery

